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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	1176
Number of Logic Elements/Cells	5292
Total RAM Bits	57344
Number of I/O	284
Number of Gates	236666
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	456-BBGA
Supplier Device Package	456-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv200-4fg456i

Virtex Device/Package Combinations and Maximum I/O

Table 3: Virtex Family Maximum User I/O by Device/Package (Excluding Dedicated Clock Pins)

Package	XCV50	XCV100	XCV150	XCV200	XCV300	XCV400	XCV600	XCV800	XCV1000
CS144	94	94							
TQ144	98	98							
PQ240	166	166	166	166	166				
HQ240						166	166	166	
BG256	180	180	180	180					
BG352			260	260	260				
BG432					316	316	316	316	
BG560						404	404	404	404
FG256	176	176	176	176					
FG456			260	284	312				
FG676						404	444	444	
FG680							512	512	512

Virtex Ordering Information



Figure 1: Virtex Ordering Information

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T_{IJITCC} parameter, changed T_{OJIT} to T_{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036, 111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V_{CCO} in CS144 package on p.43.
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed..." statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	<ul style="list-style-type: none"> Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	<ul style="list-style-type: none"> Corrected Pinout information for devices in the BG256, BG432, and BG560 packages in Table 18. Corrected BG256 Pin Function Diagram.
04/01	2.5	<ul style="list-style-type: none"> Revised minimums for Global Clock Set-Up and Hold for LVTTTL Standard, with DLL. Converted file to modularized format. See Virtex Data Sheet section.
03/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs:
Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs:
Functional Description (Module 2)
- DS003-3, Virtex 2.5V FPGAs:
DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs:
Pinout Tables (Module 4)

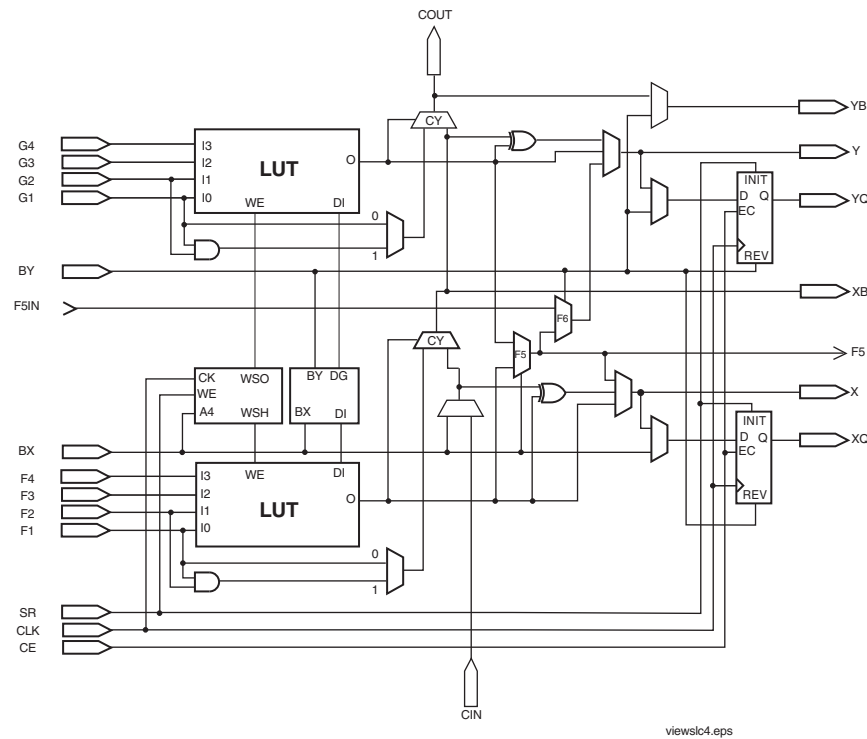


Figure 5: Detailed View of Virtex Slice

Additional Logic

The F5 multiplexer in each slice combines the function generator outputs. This combination provides either a function generator that can implement any 5-input function, a 4:1 multiplexer, or selected functions of up to nine inputs.

Similarly, the F6 multiplexer combines the outputs of all four function generators in the CLB by selecting one of the F5-multiplexer outputs. This permits the implementation of any 6-input function, an 8:1 multiplexer, or selected functions of up to 19 inputs.

Each CLB has four direct feedthrough paths, one per LC. These paths provide extra data input or additional local routing that does not consume logic resources.

Arithmetic Logic

Dedicated carry logic provides fast arithmetic carry capability for high-speed arithmetic functions. The Virtex CLB supports two separate carry chains, one per Slice. The height of the carry chains is two bits per CLB.

The arithmetic logic includes an XOR gate that allows a 1-bit full adder to be implemented within an LC. In addition, a dedicated AND gate improves the efficiency of multiplier implementation.

The dedicated carry path can also be used to cascade function generators for implementing wide logic functions.

BUFTs

Each Virtex CLB contains two 3-state drivers (BUFTs) that can drive on-chip busses. See **Dedicated Routing**, page 7. Each Virtex BUFT has an independent 3-state control pin and an independent input pin.

Block SelectRAM

Virtex FPGAs incorporate several large block SelectRAM memories. These complement the distributed LUT SelectRAMs that provide shallow RAM structures implemented in CLBs.

Block SelectRAM memory blocks are organized in columns. All Virtex devices contain two such columns, one along each vertical edge. These columns extend the full height of the chip. Each memory block is four CLBs high, and consequently, a Virtex device 64 CLBs high contains 16 memory blocks per column, and a total of 32 blocks.

Table 3 shows the amount of block SelectRAM memory that is available in each Virtex device.

Table 3: Virtex Block SelectRAM Amounts

Device	# of Blocks	Total Block SelectRAM Bits
XCV50	8	32,768
XCV100	10	40,960
XCV150	12	49,152
XCV200	14	57,344
XCV300	16	65,536
XCV400	20	81,920
XCV600	24	98,304
XCV800	28	114,688
XCV1000	32	131,072

Each block SelectRAM cell, as illustrated in Figure 6, is a fully synchronous dual-ported 4096-bit RAM with independent control signals for each port. The data widths of the two ports can be configured independently, providing built-in bus-width conversion.

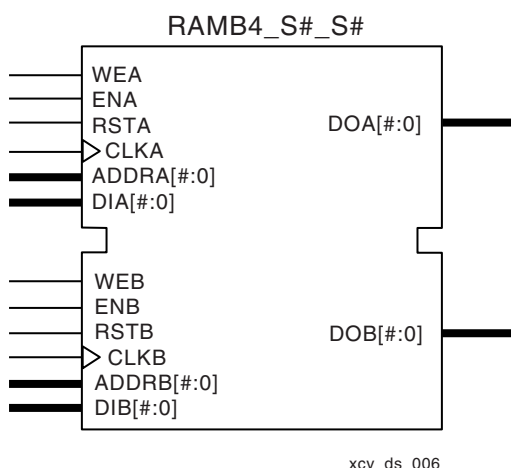


Figure 6: Dual-Port Block SelectRAM

Table 4 shows the depth and width aspect ratios for the block SelectRAM.

Table 4: Block SelectRAM Port Aspect Ratios

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

The Virtex block SelectRAM also includes dedicated routing to provide an efficient interface with both CLBs and other block SelectRAMs. Refer to XAPP130 for block SelectRAM timing waveforms.

Programmable Routing Matrix

It is the longest delay path that limits the speed of any worst-case design. Consequently, the Virtex routing architecture and its place-and-route software were defined in a single optimization process. This joint optimization minimizes long-path delays, and consequently, yields the best system performance.

The joint optimization also reduces design compilation times because the architecture is software-friendly. Design cycles are correspondingly reduced due to shorter design iteration times.

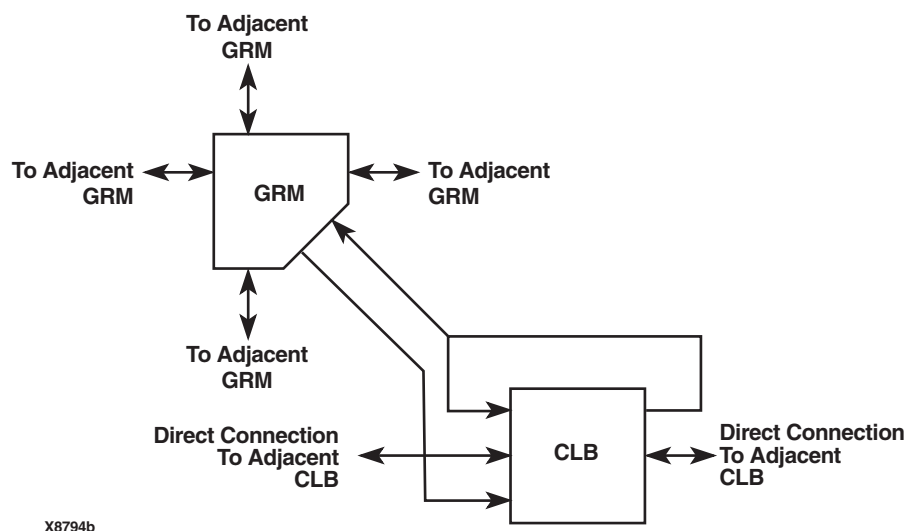


Figure 7: Virtex Local Routing

Local Routing

The VersaBlock provides local routing resources, as shown in Figure 7, providing the following three types of connections.

- Interconnections among the LUTs, flip-flops, and GRM

- Internal CLB feedback paths that provide high-speed connections to LUTs within the same CLB, chaining them together with minimal routing delay
- Direct paths that provide high-speed connections between horizontally adjacent CLBs, eliminating the delay of the GRM.

Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is

selected either from these pads or from signals in the general purpose routing.

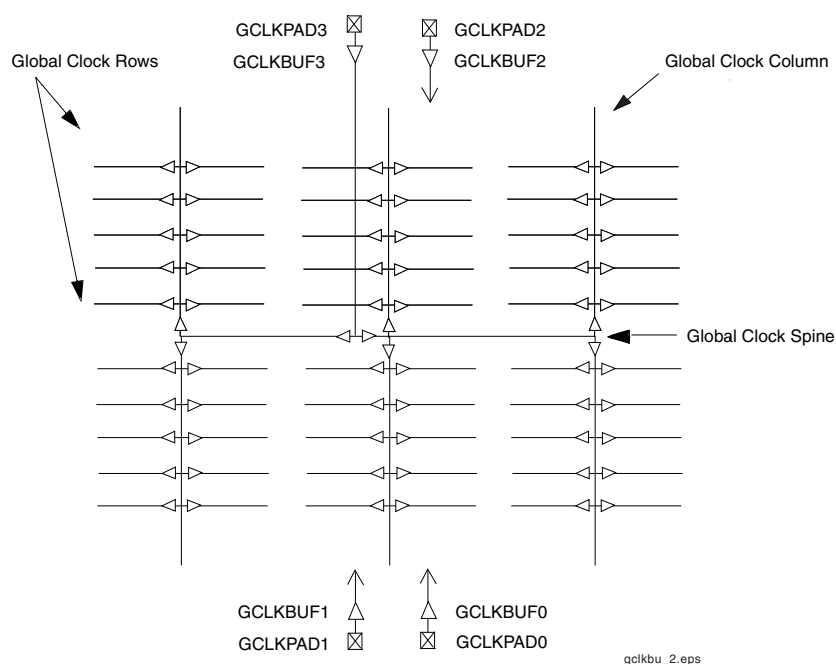


Figure 9: Global Clock Distribution Network

Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock networks. The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Clock edges reach internal flip-flops one to four clock periods after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to de-skew a board level clock among multiple Virtex devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

See **DLL Timing Parameters**, page 21 of Module 3, for frequency range information.

Boundary Scan

Virtex devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, INTEST, SAMPLE/PRELOAD, BYPASS, IDCODE, USERCODE, and HIGHZ instructions. The TAP also supports two internal scan chains and configuration/readback of the device. The TAP uses dedicated package pins that always operate using LVTTTL. For TDO to operate using LVTTTL, the V_{CCO} for Bank 2 should be 3.3 V. Otherwise, TDO switches rail-to-rail between ground and V_{CCO} .

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including un-bonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections, provided the user design or application is turned off.

Table 5 lists the boundary-scan instructions supported in Virtex FPGAs. Internal signals can be captured during EXTEST by connecting them to un-bonded or unused IOBs. They can also be connected to the unused outputs of IOBs defined as unidirectional input pins.

Before the device is configured, all instructions except USER1 and USER2 are available. After configuration, all instructions are available. During configuration, it is recommended that those operations using the boundary-scan register (SAMPLE/PRELOAD, INTEST, EXTEST) not be performed.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

Figure 10 is a diagram of the Virtex Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Instruction Set

The Virtex Series boundary scan instruction set also includes instructions to configure the device and read back configuration data (CFG_IN, CFG_OUT, and JSTART). The complete instruction set is coded as shown in **Table 5**.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out, and 3-State Control. Non-IOB pins have appropriate partial bit population if input-only or output-only. Each EXTEST CAPTURED-OR state captures all In, Out, and 3-state pins.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA supports up to two additional internal scan chains that can be specified using the BSCAN macro. The macro provides two user pins (SEL1 and SEL2) which are decoded by the USER1 and USER2 instructions respectively. For these instructions, two corresponding pins (TDO1 and TDO2) allow user scan data to be shifted out of TDO.

Likewise, there are individual clock pins (DRCK1 and DRCK2) for each user register. There is a common input pin (TDI) and shared output pins that represent the state of the TAP controller (RESET, SHIFT, and UPDATE).

Bit Sequence

The order within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contribute all three bits.

From a cavity-up view of the chip (as shown in EPIC), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in **Figure 11**.

BSDL (Boundary Scan Description Language) files for Virtex Series devices are available on the Xilinx web site in the File Download area.

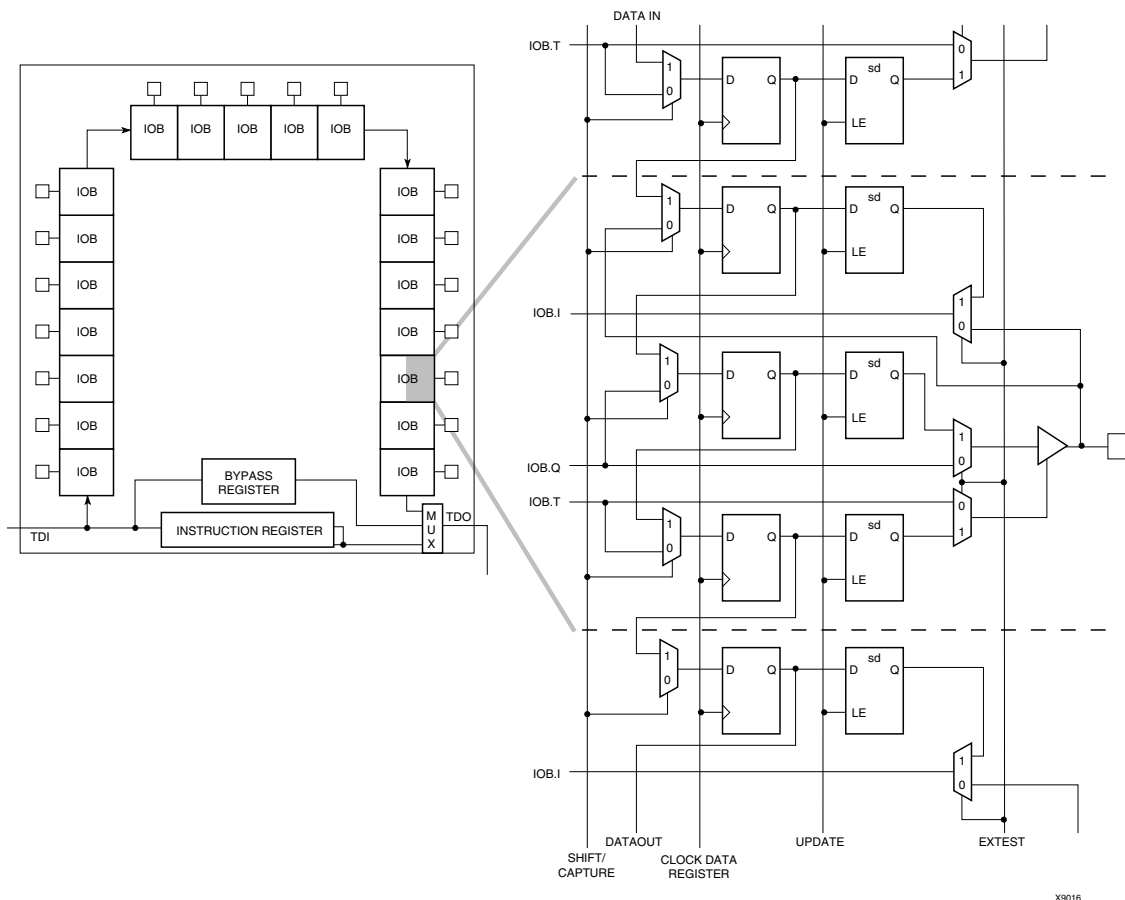


Figure 10: Virtex Series Boundary Scan Logic

ers with a common user interface regardless of their choice of entry and verification tools. The XDM software simplifies the selection of implementation options with pull-down menus and on-line help.

Application programs ranging from schematic capture to Placement and Routing (PAR) can be accessed through the XDM software. The program command sequence is generated prior to execution, and stored for documentation.

Several advanced software features facilitate Virtex design. RPMs, for example, are schematic-based macros with relative location constraints to guide their placement. They help ensure optimal implementation of common functions.

For HDL design entry, the Xilinx FPGA Foundation development system provides interfaces to the following synthesis design environments.

- Synopsys (FPGA Compiler, FPGA Express)
- Exemplar (Spectrum)
- Synplicity (Synplify)

For schematic design entry, the Xilinx FPGA Foundation and alliance development system provides interfaces to the following schematic-capture design environments.

- Mentor Graphics V8 (Design Architect, QuickSim II)
- Viewlogic Systems (Viewdraw)

Third-party vendors support many other environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Virtex FPGAs supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The “soft macro” portion of the library contains detailed descriptions of common logic functions, but does not contain any partitioning or placement information. The performance of these macros depends, therefore, on the partitioning and placement obtained during implementation.

RPMs, on the other hand, do contain predetermined partitioning and placement information that permits optimal implementation of these functions. Users can create their own library of soft macros or RPMs based on the macros and primitives in the standard library.

The design environment supports hierarchical design entry, with high-level schematics that comprise major functional blocks, while lower-level schematics define the logic in these blocks. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical

design, thus allowing the most convenient entry method to be used for each portion of the design.

Design Implementation

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF net list for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floor planning.

The implementation software incorporates Timing Wizard® timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

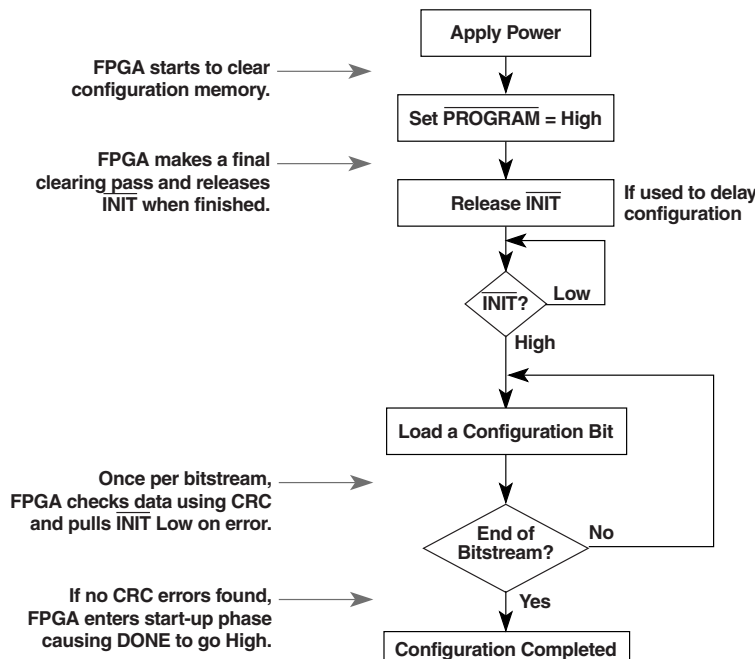
Timing requirements are entered on a schematic in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

Design Verification

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the net list for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the TRACE® static timing analyzer.

For in-circuit debugging, the development system includes a download and readback cable. This cable connects the FPGA in the target system to a PC or workstation. After downloading the design into the FPGA, the designer can single-step the logic, readback the contents of the flip-flops, and so observe the internal logic state. Simple modifications can be downloaded into the system in a matter of minutes.



ds003_154_111799

Figure 15: Serial Configuration Flowchart

After configuration, the pins of the SelectMAP port can be used as additional user I/O. Alternatively, the port can be retained to permit high-speed 8-bit readback.

Retention of the SelectMAP port is selectable on a design-by-design basis when the bitstream is generated. If retention is selected, PROHIBIT constraints are required to prevent the SelectMAP-port pins from being used as user I/O.

Multiple Virtex FPGAs can be configured using the SelectMAP mode, and be made to start-up simultaneously. To configure multiple devices in this way, wire the individual CCLK, Data, WRITE, and BUSY pins of all the devices in parallel. The individual devices are loaded separately by asserting the CS pin of each device in turn and writing the appropriate data. see Table 9 for SelectMAP Write Timing Characteristics.

Table 9: SelectMAP Write Timing Characteristics

	Description		Symbol		Units
CCLK	D ₀₋₇ Setup/Hold	1/2	T _{SMDCC} /T _{SMCCD}	5.0 / 1.7	ns, min
	$\overline{\text{CS}}$ Setup/Hold	3/4	T _{SMCSCC} /T _{SMCCCS}	7.0 / 1.7	ns, min
	$\overline{\text{WRITE}}$ Setup/Hold	5/6	T _{SMCCW} /T _{SMWCC}	7.0 / 1.7	ns, min
	BUSY Propagation Delay	7	T _{SMCKBY}	12.0	ns, max
	Maximum Frequency		F _{CC}	66	MHz, max
	Maximum Frequency with no handshake		F _{CCNH}	50	MHz, max

Write

Write operations send packets of configuration data into the FPGA. The sequence of operations for a multi-cycle write operation is shown below. Note that a configuration packet can be split into many such sequences. The packet does not have to complete within one assertion of $\overline{\text{CS}}$, illustrated in Figure 16.

1. Assert $\overline{\text{WRITE}}$ and $\overline{\text{CS}}$ Low. Note that when $\overline{\text{CS}}$ is asserted on successive CCLKs, $\overline{\text{WRITE}}$ must remain either asserted or de-asserted. Otherwise an abort will be initiated, as described below.
2. Drive data onto D[7:0]. Note that to avoid contention, the data source should not be enabled while $\overline{\text{CS}}$ is Low and $\overline{\text{WRITE}}$ is High. Similarly, while $\overline{\text{WRITE}}$ is High, no more than one $\overline{\text{CS}}$ should be asserted.

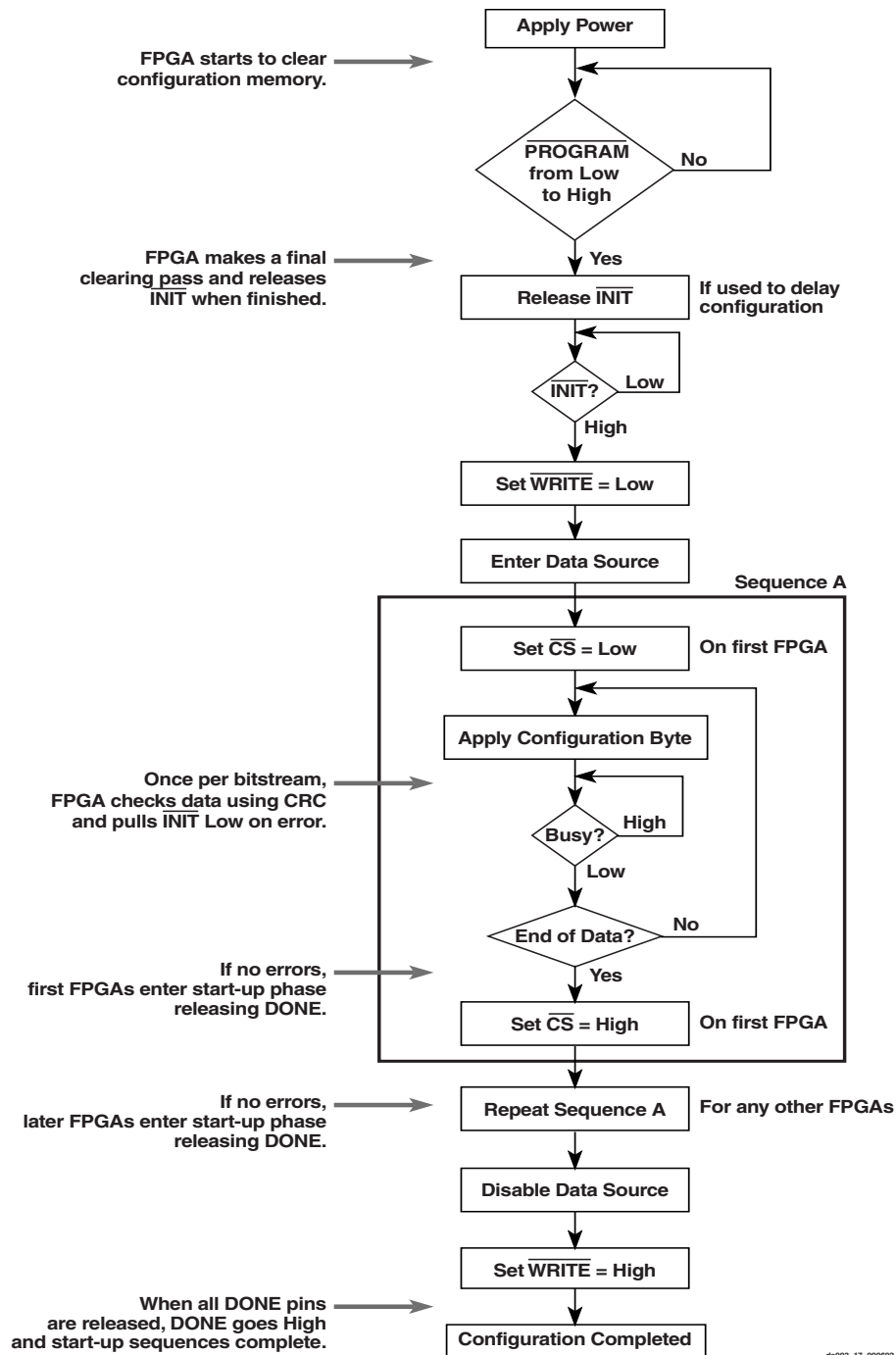


Figure 17: SelectMAP Flowchart for Write Operation

Abort

During a given assertion of \overline{CS} , the user cannot switch from a write to a read, or vice-versa. This action causes the current packet command to be aborted. The device will remain BUSY until the aborted operation has completed. Following an abort, data is assumed to be unaligned to word boundar-

ies, and the FPGA requires a new synchronization word prior to accepting any new packets.

To initiate an abort during a write operation, de-assert \overline{WRITE} . At the rising edge of CCLK, an abort is initiated, as shown in Figure 18.

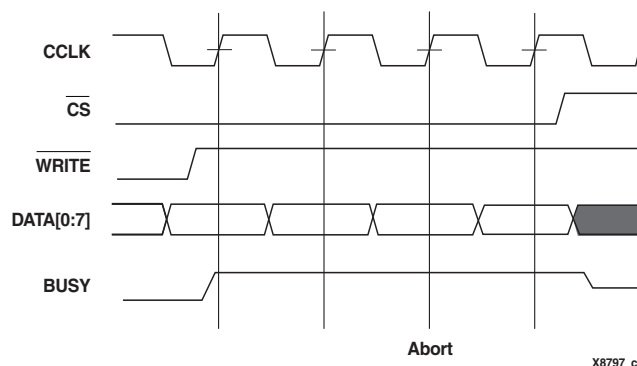


Figure 18: SelectMAP Write Abort Waveforms

Boundary-Scan Mode

In the boundary-scan mode, configuration is done through the IEEE 1149.1 Test Access Port. Note that the **PROGRAM** pin must be pulled High prior to reconfiguration. A Low on the **PROGRAM** pin resets the TAP controller and no JTAG operations can be performed.

Configuration through the TAP uses the **CFG_IN** instruction. This instruction allows data input on TDI to be converted into data packets for the internal configuration bus.

The following steps are required to configure the FPGA through the boundary-scan port (when using TCK as a start-up clock).

1. Load the **CFG_IN** instruction into the boundary-scan instruction register (IR)
2. Enter the Shift-DR (SDR) state
3. Shift a configuration bitstream into TDI
4. Return to Run-Test-Idle (RTI)
5. Load the **JSTART** instruction into IR
6. Enter the SDR state
7. Clock TCK through the startup sequence
8. Return to RTI

Configuration and readback via the TAP is always available. The boundary-scan mode is selected by a <101> or 001> on the mode pins (M2, M1, M0). For details on TAP characteristics, refer to XAPP139.

Configuration Sequence

The configuration of Virtex devices is a three-phase process. First, the configuration memory is cleared. Next, configuration data is loaded into the memory, and finally, the logic is activated by a start-up process.

Configuration is automatically initiated on power-up unless it is delayed by the user, as described below. The configuration process can also be initiated by asserting **PROGRAM**.

The end of the memory-clearing phase is signalled by **INIT** going High, and the completion of the entire process is signalled by **DONE** going High.

The power-up timing of configuration signals is shown in Figure 19. The corresponding timing characteristics are listed in Table 10.

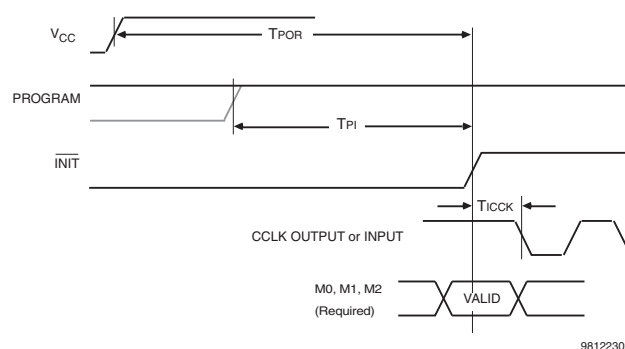


Figure 19: Power-Up Timing Configuration Signals

Table 10: Power-up Timing Characteristics

Description	Symbol	Value	Units
Power-on Reset	T _{POR}	2.0	ms, max
Program Latency	T _{PL}	100.0	μs, max
CCLK (output) Delay	T _{ICCK}	0.5	μs, min
		4.0	μs, max
Program Pulse Width	T _{PROGRAM}	300	ns, min

Delaying Configuration

INIT can be held Low using an open-drain driver. An open-drain is required since **INIT** is a bidirectional open-drain pin that is held Low by the FPGA while the configuration memory is being cleared. Extending the time that the pin is Low causes the configuration sequencer to wait. Thus, configuration is delayed by preventing entry into the phase where data is loaded.

Start-Up Sequence

The default Start-up sequence is that one CCLK cycle after **DONE** goes High, the global 3-state signal (GTS) is released. This permits device outputs to turn on as necessary.

One CCLK cycle later, the Global Set/Reset (GSR) and Global Write Enable (GWE) signals are released. This permits the internal storage elements to begin changing state in response to the logic and the user clock.

The relative timing of these events can be changed. In addition, the GTS, GSR, and GWE events can be made dependent on the **DONE** pins of multiple devices all going High, forcing the devices to start in synchronism. The sequence can also be paused at any stage until lock has been achieved on any or all DLLs.

Data Stream Format

Virtex devices are configured by sequentially loading frames of data. **Table 11** lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 “Virtex Configuration Architecture Advanced Users Guide”.

Table 11: Virtex Bit-Stream Lengths

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138: *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, “0” hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036, 111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.



Virtex™ 2.5 V Field Programmable Gate Arrays

DS003-3 (v4.0) March 1, 2013

Production Product Specification

Virtex Electrical Characteristics

Definition of Terms

Electrical and switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance: These speed files are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary: These speed files are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production: These speed files are released once enough production silicon of a particular device family member has been characterized to provide full correlation between speed files and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications. Contact the factory for design considerations requiring more detailed information.

Table 1 correlates the current status of each Virtex device with a corresponding speed file designation.

Table 1: Virtex Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XCV50			–6, –5, –4
XCV100			–6, –5, –4
XCV150			–6, –5, –4
XCV200			–6, –5, –4
XCV300			–6, –5, –4
XCV400			–6, –5, –4
XCV600			–6, –5, –4
XCV800			–6, –5, –4
XCV1000			–6, –5, –4

All specifications are subject to change without notice.

DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Device	Min	Max	Units
V_{DRINT}	Data Retention V_{CCINT} Voltage (below which configuration data can be lost)	All	2.0		V
V_{DRIO}	Data Retention V_{CCO} Voltage (below which configuration data can be lost)	All	1.2		V
I_{CCINTQ}	Quiescent V_{CCINT} supply current ^(1,3)	XCV50		50	mA
		XCV100		50	mA
		XCV150		50	mA
		XCV200		75	mA
		XCV300		75	mA
		XCV400		75	mA
		XCV600		100	mA
		XCV800		100	mA
		XCV1000		100	mA
I_{CCOQ}	Quiescent V_{CCO} supply current ⁽¹⁾	XCV50		2	mA
		XCV100		2	mA
		XCV150		2	mA
		XCV200		2	mA
		XCV300		2	mA
		XCV400		2	mA
		XCV600		2	mA
		XCV800		2	mA
		XCV1000		2	mA
I_{REF}	V_{REF} current per V_{REF} pin	All		20	μ A
I_L	Input or output leakage current	All	-10	+10	μ A
C_{IN}	Input capacitance (sample tested)	BGA, PQ, HQ, packages		8	pF
I_{RPU}	Pad pull-up (when selected) @ $V_{in} = 0$ V, $V_{CCO} = 3.3$ V (sample tested)	All	Note (2)	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ $V_{in} = 3.6$ V (sample tested)		Note (2)	0.15	mA

Notes:

1. With no output current loads, no active input pull-up resistors, all I/O pins 3-stated and floating.
2. Internal pull-up and pull-down resistors guarantee valid logic levels at unconnected input pins. These pull-up and pull-down resistors do not guarantee valid logic levels when input pins are connected to other circuits.
3. Multiply I_{CCINTQ} limit by two for industrial grade.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Clock CLK to Pad delay with OBUFT enabled (non-3-state)	T_{IOCKP}	1.0	2.9	3.2	3.5	ns, max
Clock CLK to Pad high-impedance (synchronous) ⁽¹⁾	T_{IOCKHZ}	1.1	2.3	2.5	2.9	ns, max
Clock CLK to valid data on Pad delay, plus enable delay for OBUFT	T_{IOCKON}	1.5	3.4	3.7	4.1	ns, max
Setup and Hold Times before/after Clock CLK⁽²⁾		Setup Time / Hold Time				
O input	T_{IOOCK}/T_{IOCKO}	0.51 / 0	1.1 / 0	1.2 / 0	1.3 / 0	ns, min
OCE input	$T_{IOOCECK}/T_{IOCKOCE}$	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR input (OFF)	$T_{IOSRCKO}/T_{IOCKOSR}$	0.52 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min
3-State Setup Times, T input	T_{IOTCK}/T_{IOCKT}	0.34 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
3-State Setup Times, TCE input	$T_{IOTCECK}/T_{IOCKTCE}$	0.41 / 0	0.9 / 0	0.9 / 0	1.1 / 0	ns, min
3-State Setup Times, SR input (TFF)	$T_{IOSRCKT}/T_{IOCKTSR}$	0.49 / 0	1.0 / 0	1.1 / 0	1.3 / 0	ns, min
Set/Reset Delays						
SR input to Pad (asynchronous)	T_{IOSRP}	1.6	3.8	4.1	4.6	ns, max
SR input to Pad high-impedance (asynchronous) ⁽¹⁾	T_{IOSRHZ}	1.6	3.1	3.4	3.9	ns, max
SR input to valid data on Pad (asynchronous)	T_{IOSRON}	2.0	4.2	4.6	5.1	ns, max
GSR to Pad	T_{IOGSRQ}	4.9	9.7	10.9	12.5	ns, max

Notes:

1. 3-state turn-off delays should not be adjusted.
2. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

CLB Arithmetic Switching Characteristics

Setup times not listed explicitly can be approximated by decreasing the combinatorial delays by the setup time adjustment listed. Precise values are provided by the timing analyzer.

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Combinatorial Delays						
F operand inputs to X via XOR	T _{OPX}	0.37	0.8	0.9	1.0	ns, max
F operand input to XB output	T _{OPXB}	0.54	1.1	1.3	1.4	ns, max
F operand input to Y via XOR	T _{OPY}	0.8	1.5	1.7	2.0	ns, max
F operand input to YB output	T _{OPYB}	0.8	1.5	1.7	2.0	ns, max
F operand input to COUT output	T _{OPCYF}	0.6	1.2	1.3	1.5	ns, max
G operand inputs to Y via XOR	T _{OPGY}	0.46	1.0	1.1	1.2	ns, max
G operand input to YB output	T _{OPGYB}	0.8	1.6	1.8	2.1	ns, max
G operand input to COUT output	T _{OPCYG}	0.7	1.3	1.4	1.6	ns, max
BX initialization input to COUT	T _{BXCY}	0.41	0.9	1.0	1.1	ns, max
CIN input to X output via XOR	T _{CINX}	0.21	0.41	0.46	0.53	ns, max
CIN input to XB	T _{CINXB}	0.02	0.04	0.05	0.06	ns, max
CIN input to Y via XOR	T _{CINY}	0.23	0.46	0.52	0.6	ns, max
CIN input to YB	T _{CINYB}	0.23	0.45	0.51	0.6	ns, max
CIN input to COUT output	T _{BYP}	0.05	0.09	0.10	0.11	ns, max
Multiplier Operation						
F1/2 operand inputs to XB output via AND	T _{FANDXB}	0.18	0.36	0.40	0.46	ns, max
F1/2 operand inputs to YB output via AND	T _{FANDYB}	0.40	0.8	0.9	1.1	ns, max
F1/2 operand inputs to COUT output via AND	T _{FANDCY}	0.22	0.43	0.48	0.6	ns, max
G1/2 operand inputs to YB output via AND	T _{GANDYB}	0.25	0.50	0.6	0.7	ns, max
G1/2 operand inputs to COUT output via AND	T _{GANDCY}	0.07	0.13	0.15	0.17	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾	Setup Time / Hold Time					
CIN input to FFX	T _{CCKX} /T _{CKCX}	0.50 / 0	1.0 / 0	1.2 / 0	1.3 / 0	ns, min
CIN input to FFY	T _{CCKY} /T _{CKCY}	0.53 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Virtex™ 2.5 V Field Programmable Gate Arrays

DS003-4 (v4.0) March 1, 2013

Production Product Specification

Virtex Pin Definitions

Table 1: Special Purpose Pins

Pin Name	Dedicated Pin	Direction	Description
GCK0, GCK1, GCK2, GCK3	Yes	Input	Clock input pins that connect to Global Clock Buffers. These pins become user inputs when not needed for clocks.
M0, M1, M2	Yes	Input	Mode pins are used to specify the configuration mode.
CCLK	Yes	Input or Output	The configuration Clock I/O pin: it is an input for SelectMAP and slave-serial modes, and output in master-serial mode. After configuration, it is input only, logic level = Don't Care.
PROGRAM	Yes	Input	Initiates a configuration sequence when asserted Low.
DONE	Yes	Bidirectional	Indicates that configuration loading is complete, and that the start-up sequence is in progress. The output can be open drain.
INIT	No	Bidirectional (Open-drain)	When Low, indicates that the configuration memory is being cleared. The pin becomes a user I/O after configuration.
BUSY/ DOUT	No	Output	In SelectMAP mode, BUSY controls the rate at which configuration data is loaded. The pin becomes a user I/O after configuration unless the SelectMAP port is retained. In bit-serial modes, DOUT provides header information to downstream devices in a daisy-chain. The pin becomes a user I/O after configuration.
D0/DIN, D1, D2, D3, D4, D5, D6, D7	No	Input or Output	In SelectMAP mode, D0 - D7 are configuration data pins. These pins become user I/Os after configuration unless the SelectMAP port is retained. In bit-serial modes, DIN is the single data input. This pin becomes a user I/O after configuration.
WRITE	No	Input	In SelectMAP mode, the active-low Write Enable signal. The pin becomes a user I/O after configuration unless the SelectMAP port is retained.
CS	No	Input	In SelectMAP mode, the active-low Chip Select signal. The pin becomes a user I/O after configuration unless the SelectMAP port is retained.
TDI, TDO, TMS, TCK	Yes	Mixed	Boundary-scan Test-Access-Port pins, as defined in IEEE 1149.1.
DXN, DXP	Yes	N/A	Temperature-sensing diode pins. (Anode: DXP, cathode: DXN)
V _{CCINT}	Yes	Input	Power-supply pins for the internal core logic.
V _{CCO}	Yes	Input	Power-supply pins for the output drivers (subject to banking rules)
V _{REF}	No	Input	Input threshold voltage pins. Become user I/Os when an external threshold voltage is not needed (subject to banking rules).
GND	Yes	Input	Ground

Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V_{CCO}	All	Banks 0 and 1: A2, A13, D7 Banks 2 and 3: B12, G11, M13 Banks 4 and 5: N1, N7, N13 Banks 6 and 7: B2, G2, M2	No I/O Banks in this package: 1, 17, 37, 55, 73, 92, 109, 128	No I/O Banks in this package: 15, 30, 44, 61, 76, 90, 105, 121, 136, 150, 165, 180, 197, 212, 226, 240
V_{REF} Bank 0 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	C4, D6	5, 13	218, 232
	XCV100/150	... + B4	... + 7	... + 229
	XCV200/300	N/A	N/A	... + 236
	XCV400	N/A	N/A	... + 215
	XCV600	N/A	N/A	... + 230
	XCV800	N/A	N/A	... + 222
V_{REF} Bank 1 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	A10, B8	22, 30	191, 205
	XCV100/150	... + D9	... + 28	... + 194
	XCV200/300	N/A	N/A	... + 187
	XCV400	N/A	N/A	... + 208
	XCV600	N/A	N/A	... + 193
	XCV800	N/A	N/A	... + 201
V_{REF} Bank 2 (V_{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V_{REF} pins are general I/O.	XCV50	D11, F10	42, 50	157, 171
	XCV100/150	... + D13	... + 44	... + 168
	XCV200/300	N/A	N/A	... + 175
	XCV400	N/A	N/A	... + 154
	XCV600	N/A	N/A	... + 169
	XCV800	N/A	N/A	... + 161

Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V_{REF} Bank 6 (V _{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	H2, K1	116, 123	36, 50
	XCV100/150	... + J3	... + 118	... + 47
	XCV200/300	N/A	N/A	... + 54
	XCV400	N/A	N/A	... + 33
	XCV600	N/A	N/A	... + 48
	XCV800	N/A	N/A	... + 40
V_{REF} Bank 7 (V _{REF} pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	D4, E1	133, 140	9, 23
	XCV100/150	... + D2	... + 138	... + 12
	XCV200/300	N/A	N/A	... + 5
	XCV400	N/A	N/A	... + 26
	XCV600	N/A	N/A	... + 11
	XCV800	N/A	N/A	... + 19
GND	All	A1, B9, B11, C7, D5, E4, E11, F1, G10, J1, J12, L3, L5, L7, L9, N12	9, 18, 26, 35, 46, 54, 64, 75, 83, 91, 100, 111, 120, 129, 136, 144,	1, 8, 14, 22, 29, 37, 45, 51, 59, 69, 75, 83, 91, 98, 106, 112, 119, 129, 135, 143, 151, 158, 166, 172, 182, 190, 196, 204, 211, 219, 227, 233

Table 3: Virtex Pinout Tables (BGA) (Continued)

Pin Name	Device	BG256	BG352	BG432	BG560
V _{CCO} , Bank 7	All	G4, H4	G23, K26, N23	A31, L28, L31	C32, D33, K33, N32, T33
V _{REF} Bank 0 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	A8, B4	N/A	N/A	N/A
	XCV100/150	... + A4	A16, C19, C21	N/A	N/A
	XCV200/300	... + A2	... + D21	B19, D22, D24, D26	N/A
	XCV400	N/A	N/A	... + C18	A19, D20, D26, E23, E27
	XCV600	N/A	N/A	... + C24	... + E24
	XCV800	N/A	N/A	... + B21	... + E21
	XCV1000	N/A	N/A	N/A	... + D29
V _{REF} Bank 1 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	A17, B12	N/A	N/A	N/A
	XCV100/150	... + B15	B6, C9, C12	N/A	N/A
	XCV200/300	... + B17	... + D6	A13, B7, C6, C10	N/A
	XCV400	N/A	N/A	... + B15	A6, D7, D11, D16, E15
	XCV600	N/A	N/A	... + D10	... + D10
	XCV800	N/A	N/A	... + B12	... + D13
	XCV1000	N/A	N/A	N/A	... + E7
V _{REF} Bank 2 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.	XCV50	C20, J18	N/A	N/A	N/A
	XCV100/150	... + F19	E2, H2, M4	N/A	N/A
	XCV200/300	... + G18	... + D2	E2, G3, J2, N1	N/A
	XCV400	N/A	N/A	... + R3	G5, H4, L5, P4, R1
	XCV600	N/A	N/A	... + H1	... + K5
	XCV800	N/A	N/A	... + M3	... + N5
	XCV1000	N/A	N/A	N/A	... + B3

TQ144 Pin Function Diagram

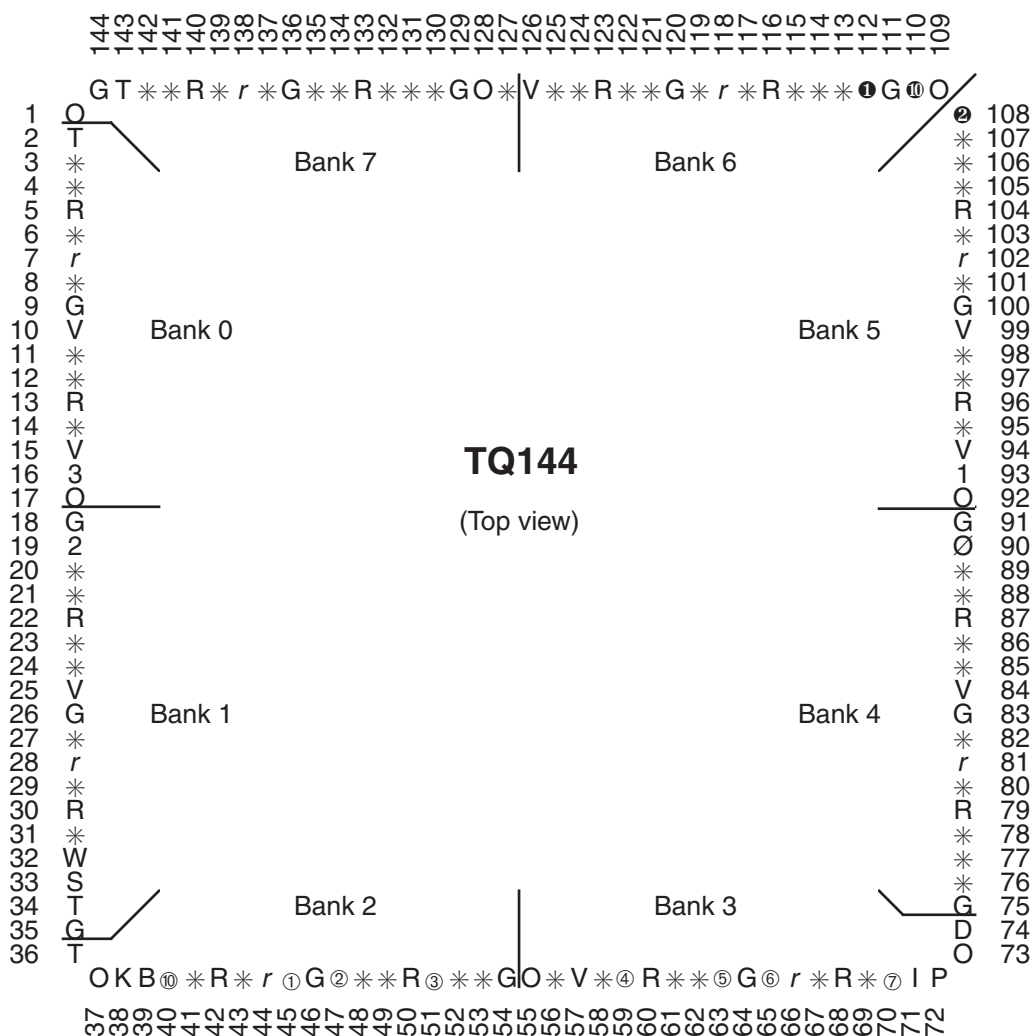


Figure 2: TQ144 Pin Function Diagram